

Title (en)

INTEGRATED CIRCUIT MARGIN MEASUREMENT AND FAILURE PREDICTION DEVICE

Title (de)

INTEGRIERTE SCHALTUNGSMARGENMESS- UND AUSFALLVORHERSAGEVORRICHTUNG

Title (fr)

DISPOSITIF DE MESURE DE MARGE DE CIRCUIT INTÉGRÉ ET DE PRÉDICTION DE DÉFAILLANCE

Publication

EP 3710844 B1 20240207 (EN)

Application

EP 18877539 A 20181115

Priority

- US 201762586423 P 20171115
- IL 2018051234 W 20181115

Abstract (en)

[origin: WO2019097516A1] A semiconductor integrated circuit (IC) comprising a signal path combiner, comprising a plurality of input paths and an output path. The IC comprises a delay circuit having an input electrically connected to the output path, the delay circuit delaying an input signal by a variable delay time to output a delayed signal path. The IC may comprise a first storage circuit electrically connected to the output path and a second storage circuit electrically connected to the delayed signal path. The IC comprises a comparison circuit that compares outputs of the signal path combiner and the delayed signal, wherein the comparison circuit comprises a comparison output provided in a comparison data signal to at least one mitigation circuit.

IPC 8 full level

G01R 31/3193 (2006.01); **G01R 31/28** (2006.01); **G01R 31/30** (2006.01)

CPC (source: CN EP IL KR US)

G01R 31/2851 (2013.01 - CN); **G01R 31/2881** (2013.01 - EP IL KR US); **G01R 31/3016** (2013.01 - EP IL KR US);
G01R 31/3193 (2013.01 - CN EP IL); **G01R 31/31937** (2013.01 - EP IL KR); **G01R 31/52** (2020.01 - CN)

Designated contracting state (EPC)

AL AT BE BG CH CY CZ DE DK EE ES FI FR GB GR HR HU IE IS IT LI LT LU LV MC MK MT NL NO PL PT RO RS SE SI SK SM TR

DOCDB simple family (publication)

WO 2019097516 A1 20190523; CN 111587378 A 20200825; CN 111587378 B 20230404; CN 116256624 A 20230613;
EP 3710844 A1 20200923; EP 3710844 A4 20210825; EP 3710844 B1 20240207; EP 4328596 A2 20240228; EP 4328596 A3 20240522;
ES 2974290 T3 20240626; IL 274688 A 20200630; IL 306080 A 20231101; JP 2021503091 A 20210204; JP 2022172206 A 20221115;
JP 7130757 B2 20220905; KR 102493473 B1 20230131; KR 20200085323 A 20200714; KR 20230020571 A 20230210;
TW 201924219 A 20190616; TW 202341663 A 20231016; TW I806927 B 20230701; US 11385282 B2 20220712; US 11841395 B2 20231212;
US 2020393506 A1 20201217; US 2023046999 A1 20230216; US 2024036105 A1 20240201

DOCDB simple family (application)

IL 2018051234 W 20181115; CN 201880085236 A 20181115; CN 202310252063 A 20181115; EP 18877539 A 20181115;
EP 23220748 A 20181115; ES 18877539 T 20181115; IL 27468820 A 20200514; IL 30608023 A 20230919; JP 2020545016 A 20181115;
JP 2022133215 A 20220824; KR 20207016661 A 20181115; KR 20237002918 A 20181115; TW 107140631 A 20181115;
TW 112119907 A 20181115; US 201816764056 A 20181115; US 202217862142 A 20220711; US 202318377016 A 20231005